

April 2000

# FQAF70N15

### **N-Channel Power MOSFET**

## **General Description**

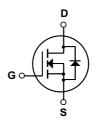
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifire, high efficiency switching for DC/DC converters, and DC motor control, uninterrupted power supply.

#### **Features**

- 44A, 150 V,  $R_{DS(on)}$  = 0.028  $\Omega$  @  $V_{GS}$  = 10 V Low gate charge ( typical 135 nC)
- Low Crss (typical 135 nC)
- · Fast switching
- · 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQAF70N15	Units
V <sub>DSS</sub>	Drain-Source Voltage		150	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		44	Α
	- Continuous (T <sub>C</sub> = 100°C)		31	Α
I <sub>DM</sub>	Drain Curent - Pulsed	(Note 1)	176	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	1000	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	44	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	13	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		130	W
	- Derate above 25°C		0.86	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.16	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	150			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°0		0.15		V/°C
I <sub>DSS</sub>	7 Oata Wallana Barin O and	V <sub>DS</sub> = 150 V, V <sub>GS</sub> = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120 V, T <sub>C</sub> = 150°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics		•		•	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 22 A		0.023	0.028	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 22 A (Note 4	)	40		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		4150 840	5400 1100	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			135	175	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 75 V, I <sub>D</sub> = 70 A,		60	130	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		420	850	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			340	690	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4,	5)	290	590	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 120 V, I <sub>D</sub> = 70 A,		135	175	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		25		nC
$Q_{gd}$	Gate-Drain Charge	(Note 4,	5)	65		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				44	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current			176	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 44 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 70 A,		150		ns
		dl <sub>F</sub> / dt = 100 A/μs (Note 4	-			

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.86mH, I<sub>AS</sub> = 44A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  70A, di/dt  $\leq$  300A/μs, V<sub>DD</sub> = BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

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# **Typical Characteristics**

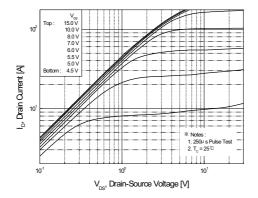


Figure 1. On-Region Characteristics

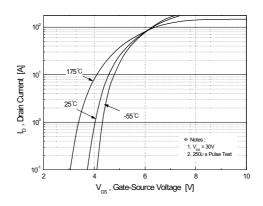


Figure 2. Transfer Characteristics

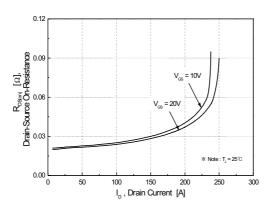


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

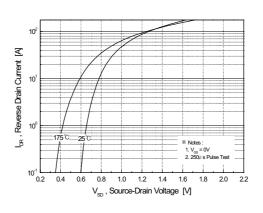


Figure 4. Body Diode Forward Voltage Variation vs. Source Current

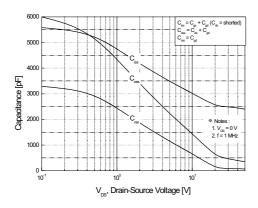


Figure 5. Capacitance Characteristics

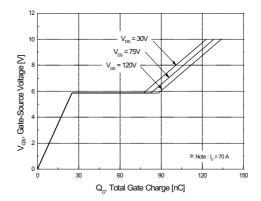
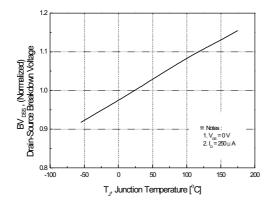


Figure 6. Gate Charge Characteristics

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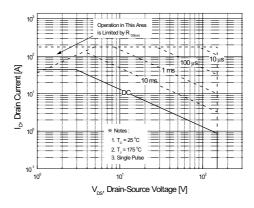
# Typical Characteristics (Continued)



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Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



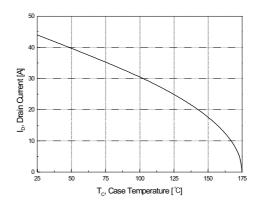


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

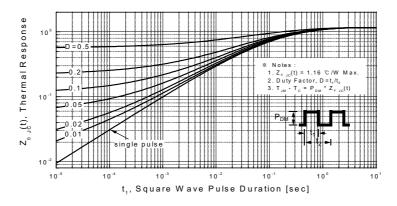
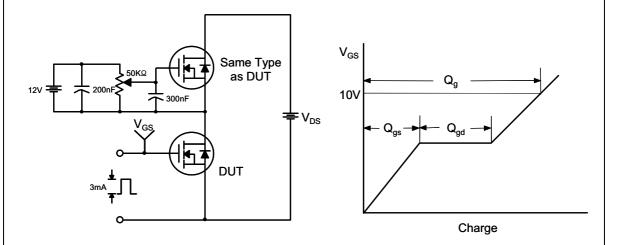


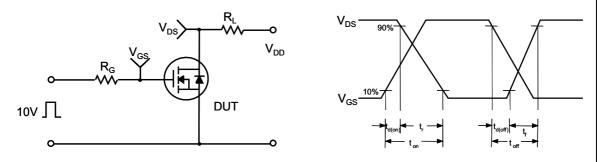
Figure 11. Transient Thermal Response Curve

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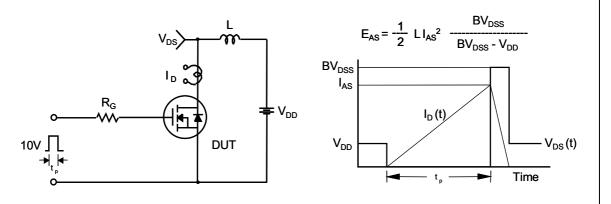
## **Gate Charge Test Circuit & Waveform**



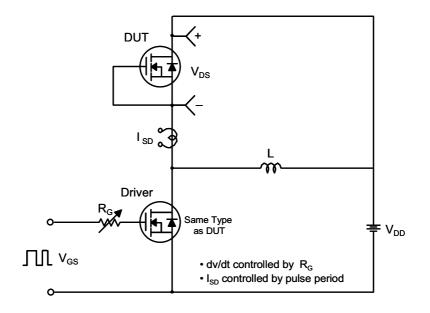
## **Resistive Switching Test Circuit & Waveforms**

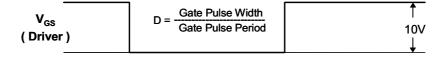


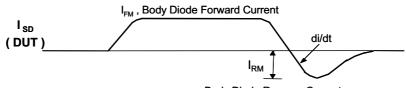
## **Unclamped Inductive Switching Test Circuit & Waveforms**



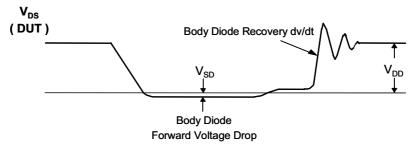
### Peak Diode Recovery dv/dt Test Circuit & Waveforms



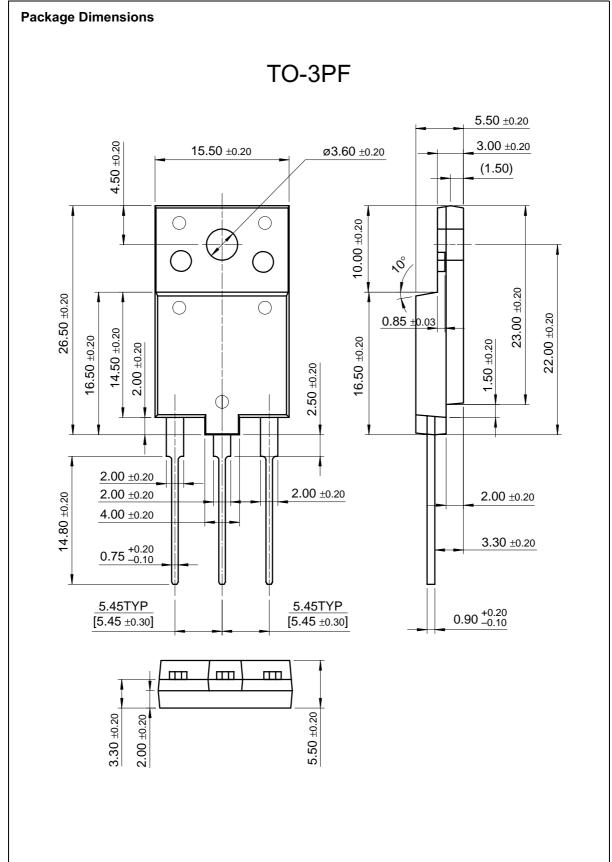




Body Diode Reverse Current



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